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PPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/620,285	07/14/2003	Robert C. Pack	CA7010492001	7734
23639 75	90 02/10/2006		EXAMINER	
BINGHAM, MCCUTCHEN LLP THREE EMBARCADERO CENTER			TAT, BINH C	
18 FLOOR		ART UNIT	PAPER NUMBER	
SAN FRANCISCO, CA 94111-4067			2825	
			DATE MAILED: 02/10/2006	

Please find below and/or attached an Office communication concerning this application or proceeding.

		<u> </u>
	Application No.	Applicant(s)
	10/620,285	PACK ET AL.
Office Action Summary	Examiner	Art Unit
	Binh C. Tat	2825
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period w  - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim rill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D. (35 U.S.C. § 133).
Status		
Responsive to communication(s) filed on <u>21 Not</u> This action is <b>FINAL</b> . 2b)⊠ This     Since this application is in condition for alloware closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro	
Disposition of Claims		
<ul> <li>4)  Claim(s) 1-36 is/are pending in the application.</li> <li>4a) Of the above claim(s) 1-5 and 16-36 is/are solution.</li> <li>5)  Claim(s) is/are allowed.</li> <li>6)  Claim(s) 6-15 is/are rejected.</li> <li>7)  Claim(s) is/are objected to.</li> <li>8)  Claim(s) are subject to restriction and/or</li> </ul>	withdrawn from consideration.	
Application Papers		
9) The specification is objected to by the Examine 10) The drawing(s) filed on 21 November 2005 is/al Applicant may not request that any objection to the c Replacement drawing sheet(s) including the correction 11) The oath or declaration is objected to by the Ex	re: a) $\square$ accepted or b) $\square$ object drawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list of	s have been received. s have been received in Application ity documents have been receive I (PCT Rule 17.2(a)).	on No ed in this National Stage
Attachment(s)  Notice of References Cited (PTO-892)  Notice of Draftsperson's Patent Drawing Review (PTO-948)  Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08), Paper No(s)/Mail Date 11/21/05, 11/30/05, 7/25/05,	4)  Interview Summary Paper No(s)/Mail Da 5)  Notice of Informal P 6)  Other:	

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## **DETAILED ACTION**

1. This office action is in response to application 10/620285 filed on 06/24/03. The examiner acknowledges: the election of group II, claims 6-15 without traverse. The withdraw of non-election claims 1-5, and 16-36.

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- Claims 6-15 are rejected under 35 U.S.C. 102(e) as being anticipated by LaCour et al.
   (U.S Patent 6901574).
- 3. As to claim 6, LaCour et al. teach a method for generating a lithography mask (see fig 1 col. 3 lines 40-55) or a printed wafer, comprising: generating integrated circuit design data (see fig 1, 3 col 3 lines 40 to col 4 line 13); analyzing the integrated circuit design data to generate context information for each feature without the use of tags (see fig 1-5 col 4 line 38 to col 9 line 39); and using the context information to write each feature of the mask or printed wafer (see 1-5 col 3 lines 40 to col 4 line 13 and col 4 line 38 to col 9 line 39).
- 4. As to claim 7, LaCour et al. teach wherein using context information comprises: analyzing mask features for contextual priority (see fig 1, 3 col 3 lines 40 to col 4 line 13 and background).

5. As to claim 8, LaCour et al. teach wherein using context information comprises: assigning priorities to the mask features (see fig 1, 3 col 3 lines 40 to col 4 line 13 and background).

6. As to claim 9, LaCour et al. teach wherein assigning priorities to the mask features comprises: applying criteria to mask design data by manual process (see fig 1, 3 col 3 lines 40 to col 4 line 13 and background).

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- 7. As to claim 10, LaCour et al. teach wherein assigning priorities to the mask features comprises: applying criteria to mask design data by computer-aided automated process (see col 1 lines 33 to col 2 lines 20).
- 8. As to claim 11, LaCour et al. teach wherein using context information comprising: analyzing mask features to determine the circuit element expected to be produced by a lithography system at a chip wafer surface (see fig 1, 3, 4 col 3 lines 8 to col 4 lines 62).
- 9. As to claim 12, LaCour et al. teach further comprising: configuring a mask design database to include additional contextual mask design data generated in using the contextual information from the integrated circuit design data (see fig 1-5 col 4 line 38 to col 9 line 39).
- 10. As to claim 13, LaCour et al. teach further comprising: configuring the mask design database to optimize an order of mask design data for use by a mask writing system (see 1-5 col 3 lines 40 to col 4 line 13 and col 4 line 38 to col 9 line 39).
- 11. As to claim 14, LaCour et al. teach wherein using context information comprises: passing context information to a mask writing system (see 1-5 col 3 lines 40 to col 4 line 13 and col 4 line 38 to col 9 line 39 and background).

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*12.* As to claim 15, LaCour et al. teach wherein using context information comprises: controlling a mask writing system base on the context information (see fig 1-5 col 4 line 38 to col 9 line 39 and abstraction).

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Binh C. Tat whose telephone number is 571 272-1908. The examiner can normally be reached on 7:30 - 4:00 (M-F).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Chiang can be reached on 571 272 7483. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Binh Tat

February 2, 2006

PAUL DINH

PRIMARY EXAMINER